

# Powder Diffraction

R.J. Hill	The Background in X-Ray Powder Diffractograms: A Case Study of Rietveld Analysis of Minor Phases Using Ni-Filtered and Graphite-Monochromated Radiation	63
N.J. Elton, P.D. Salt and J.M. Adams	The Determination of Low Levels of Quartz in Commercial Kaolins by X-ray Diffraction	71
R. Vasudevan, R. Ramesh, B. Pathiraj and B.H. Kolster	A Simplified Correction for Surface Roughness Effects in X-Ray Diffractometric Investigations	77
J. Timmers, N.M. van der Pers, G.J.M. Sprong, Th.H. de Keijser, R. Delhez	Notes on Slits and Monochromators in Accurate Powder Diffractometry	83
C.E. Matulis and J.C. Taylor	Intensity Calibration Curves for Bragg-Brentano X-Ray Diffractometers	89
Q. Johnson	Validation of Reference Patterns by Search/Matching	95
B.J. Reardon, C.R. Hubbard	A Review of the XRD Data of the Phases Present in the CaO-SrO-PbO System	96
N.R. Serebryanaya	The Crystal Structure of Pressure-Induced Phases of $\text{In}_2\text{Te}_3$ and $\text{Ga}_2\text{Te}_3$	99
H. Wulff, U. Guth and B. Loescher	The Crystal Structure of $\text{K}_2\text{REZr}(\text{PO}_4)_3$ (RE = Y, Gd) Isotypic with Langbeinite	103
G.C. Che and M. Ellner	Powder Crystal Data for the High-Temperature Phases $\text{Cu}_4\text{In}$ , $\text{Cu}_9\text{In}_4(\text{h})$ and $\text{Cu}_2\text{In}(\text{h})$	107
C.J. Rawn, R.S. Roth and H.F. McMurdie	Powder X-Ray Diffraction Data for $\text{Ca}_2\text{Bi}_2\text{O}_5$ and $\text{C}_4\text{Bi}_6\text{O}_{13}$	109
A. Mottana, S. Fiori and G.C. Parodi	Improved X-Ray Powder Diffraction Data for Franckeite	112
T.L. Aselage and M.O. Eatough	Powder X-Ray Diffraction Data for the Superconducting Phase $\text{TlCaBa}_2\text{Cu}_2\text{O}_{7.8}$	115
	International Report	117
	Calendar of Meetings	118
	Meeting Reports	120
	Short Courses and Workshops	122
	Commercial Announcements	123



Volume 7 Number 2 June 1992

Powder Diffraction An international journal of materials characterization

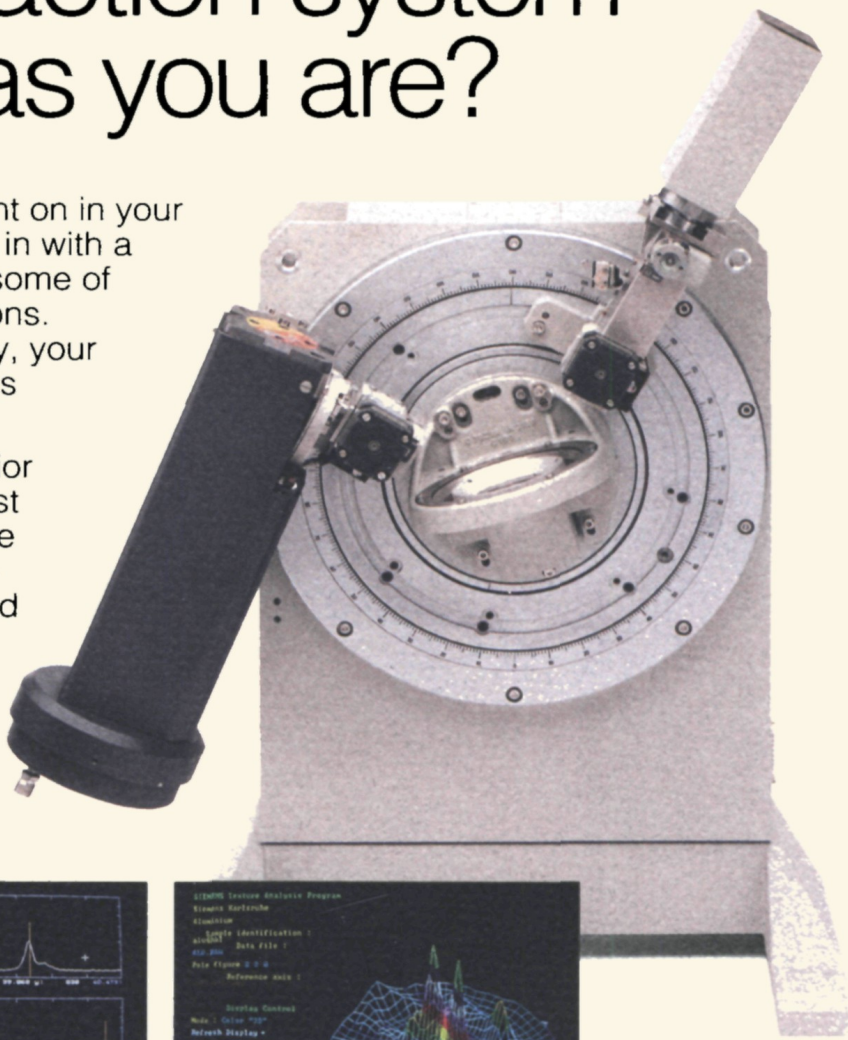
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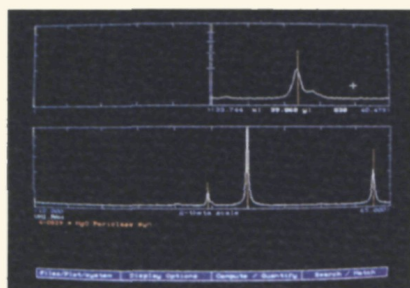
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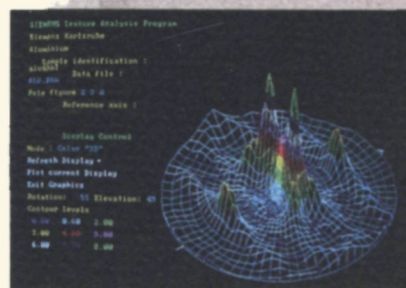
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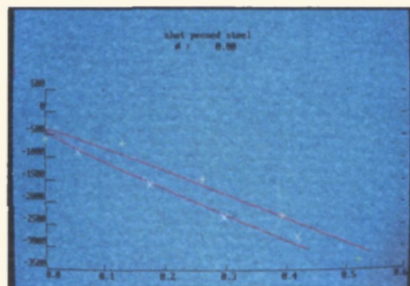
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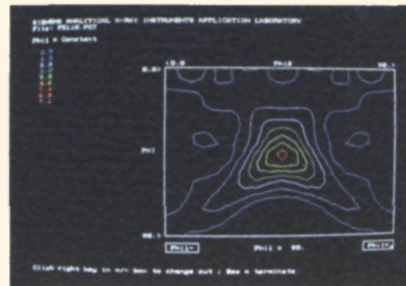
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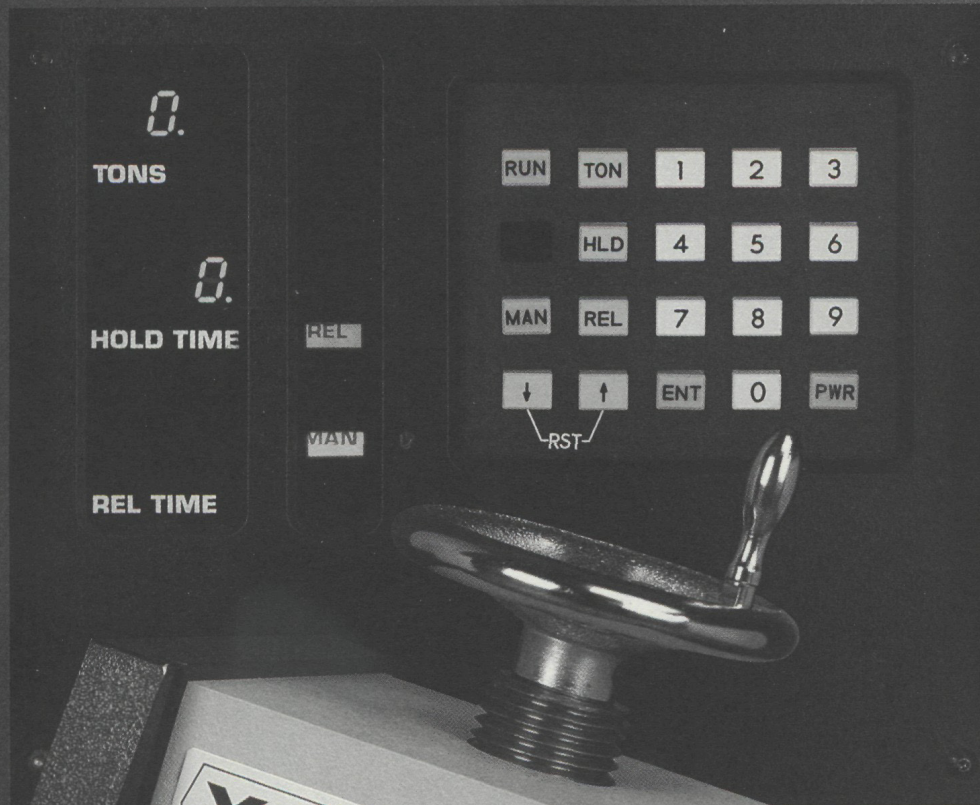
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*Subscriptions.* The annual subscription rate in the United States and Canada is \$55.00; Library; \$95.00; other than U.S.A., Canada and the Far East, the annual subscription is \$75.00. Subscriptions to the Far East, including Japan, China, Taiwan, Malaysia, the Philippines, Indonesia and Korea should be made via Sanyo Information System Corp., Taiyo Bldg. 7-7, Tomizawa-cho Nihonbashi, Chuo-ku, Tokyo 103, Japan. Airmail delivery available for subscribers outside U.S./Canada for an additional cost of \$35.00 per volume (4 issues).

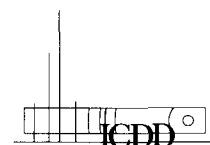
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*Postal Information.* Powder Diffraction (ISSN 0885-7156) is published quarterly for \$55.00 a year (U.S. and Canada) by JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, Pennsylvania 19081. JCPDS principal office: 1601 Park Lane, Swarthmore, Pa. 19081. Julian Messick, Jr., General Manager. © 1990 JCPDS-International Centre for Diffraction Data. Postmaster: Send address changes to JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, Pennsylvania 19081.

International CODEN Service (Intercode): PODIE2  
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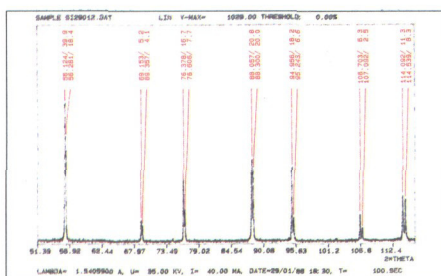




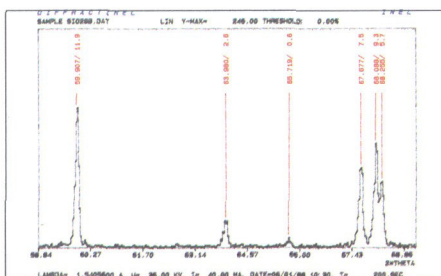
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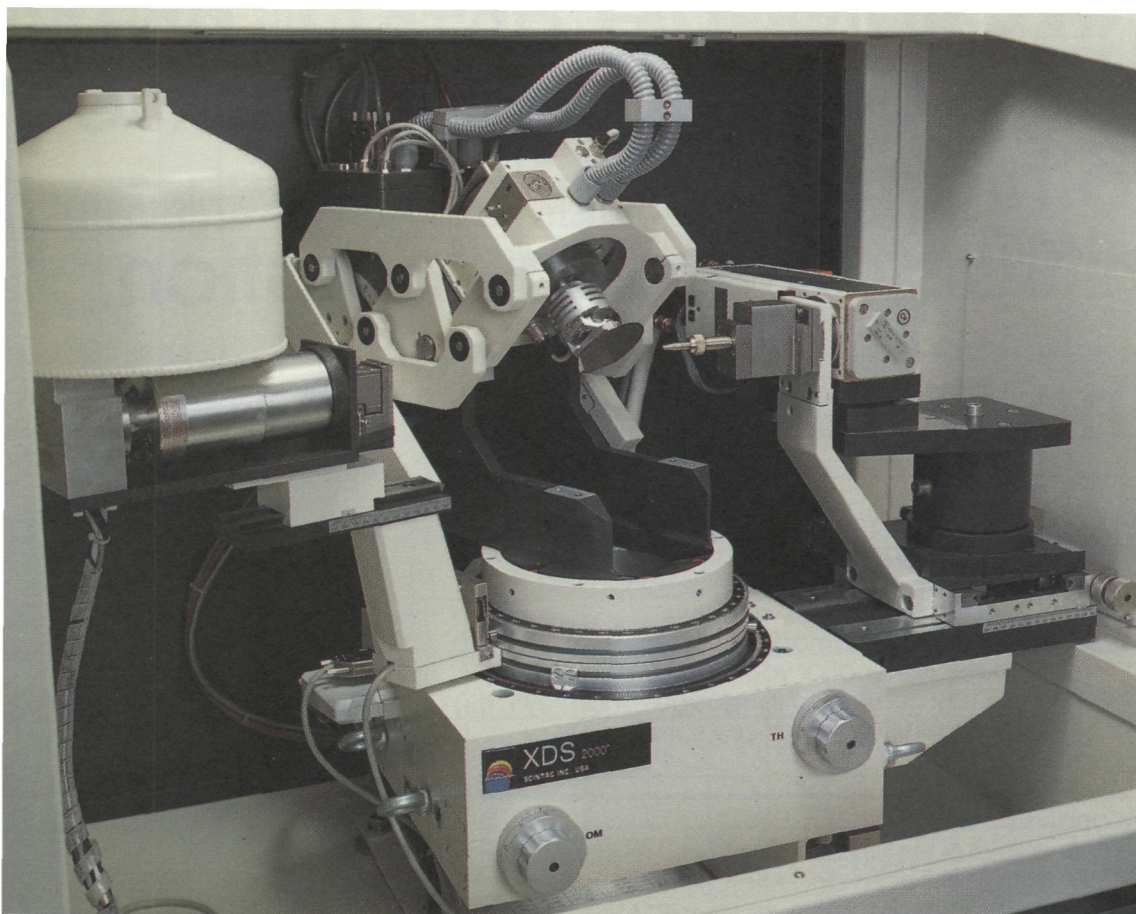
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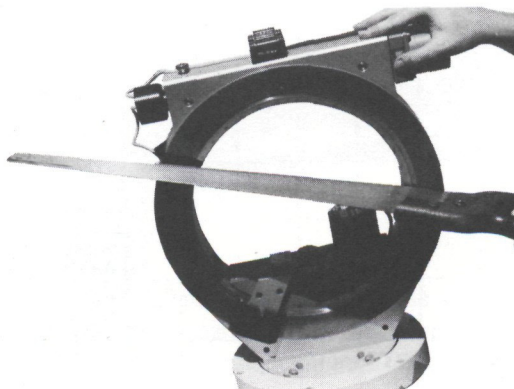


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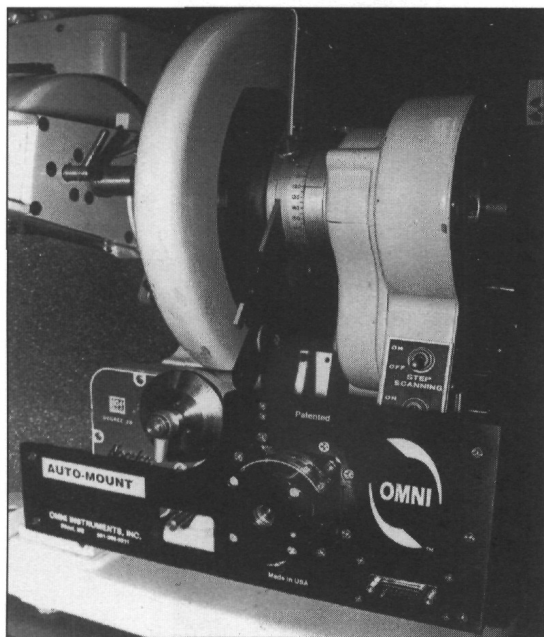


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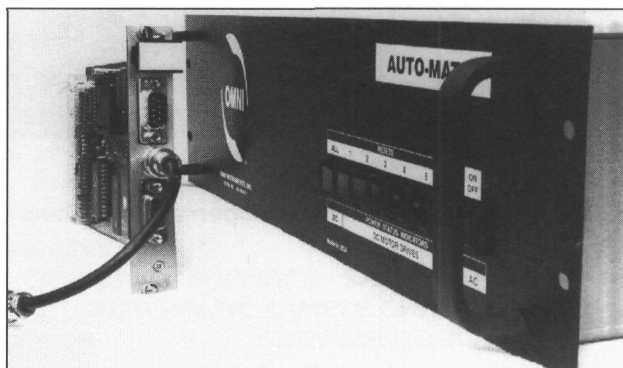
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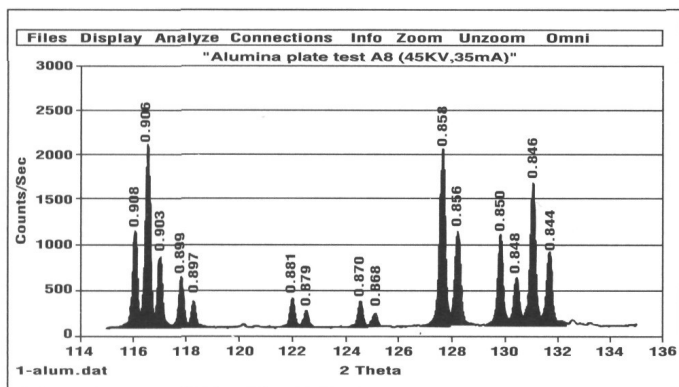
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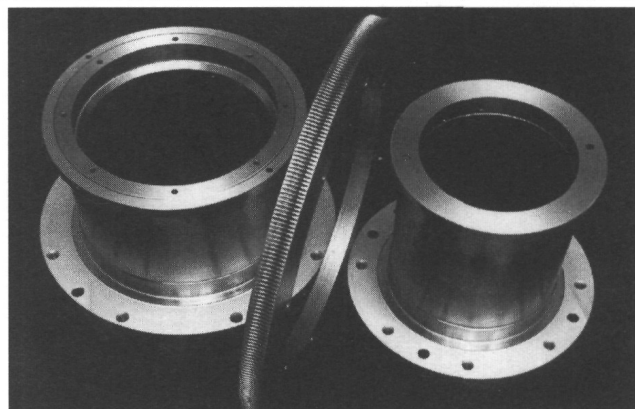


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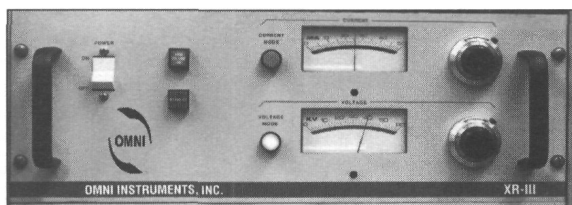
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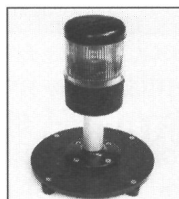


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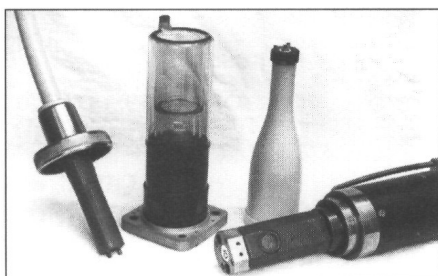
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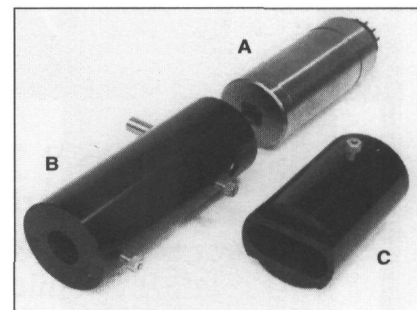
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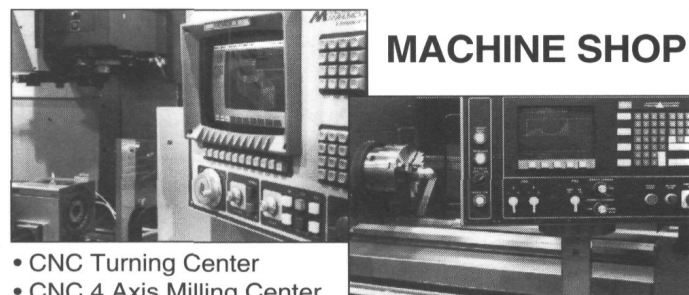


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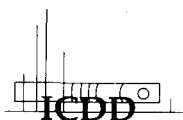
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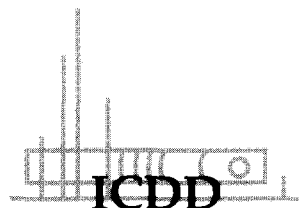
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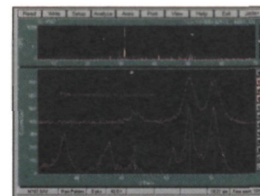
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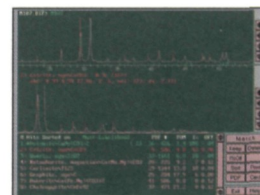


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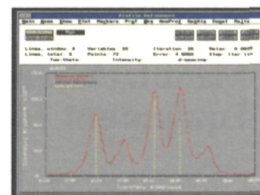
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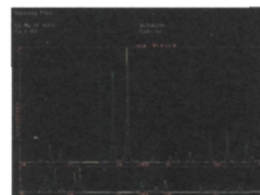
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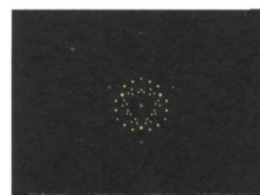
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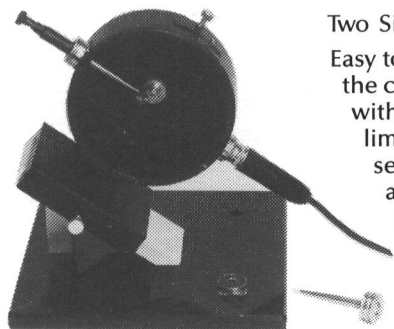
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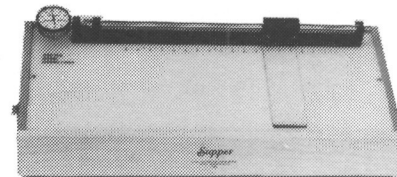
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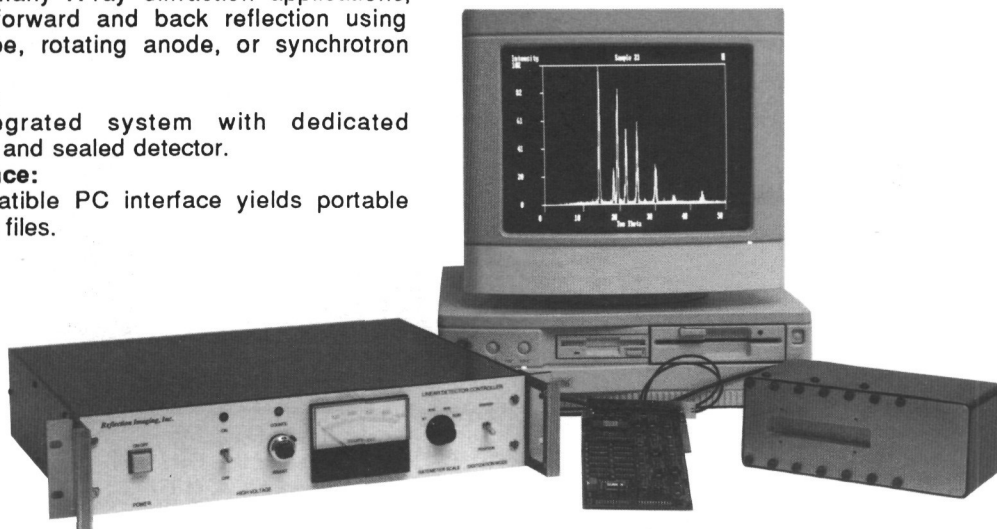
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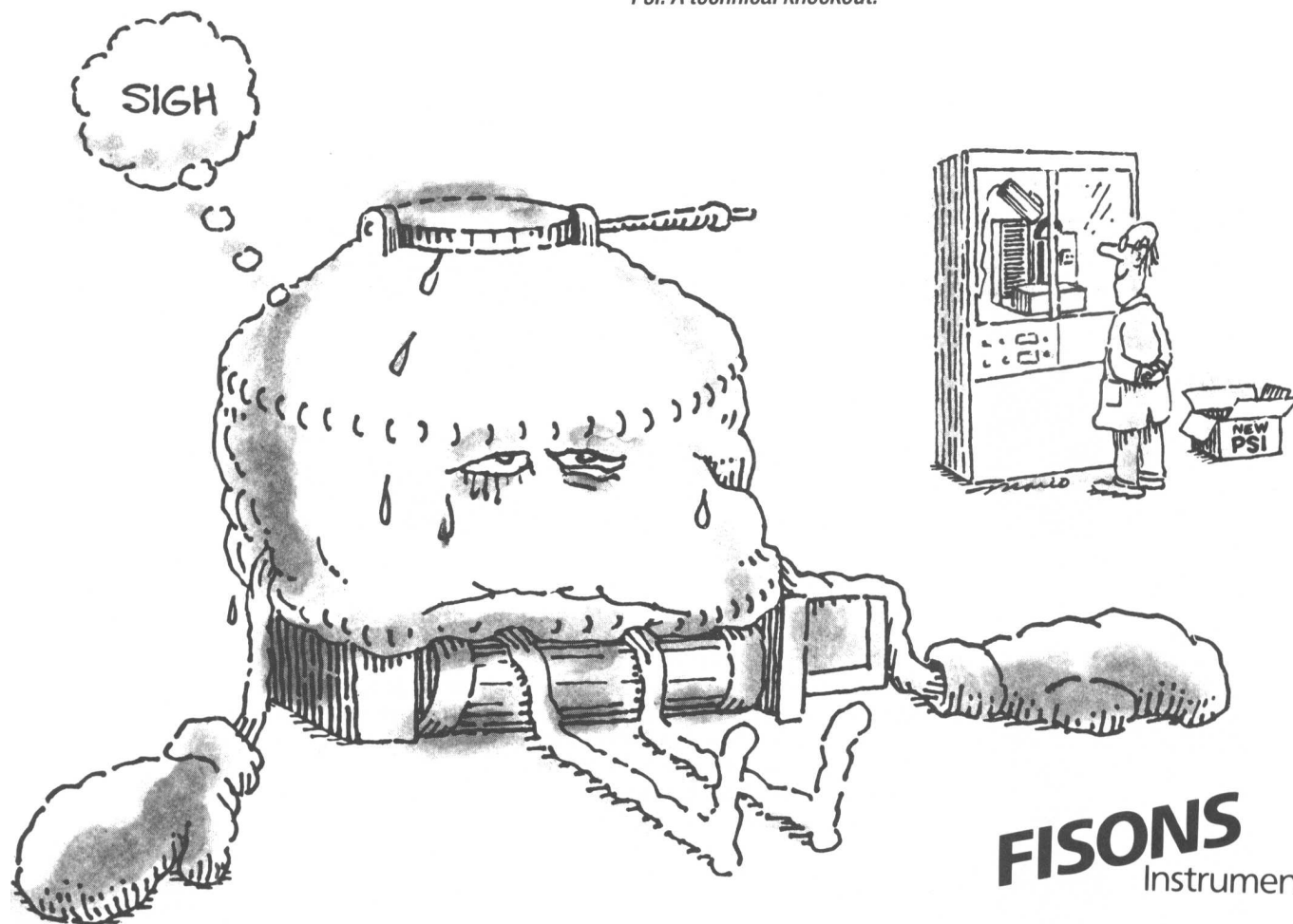
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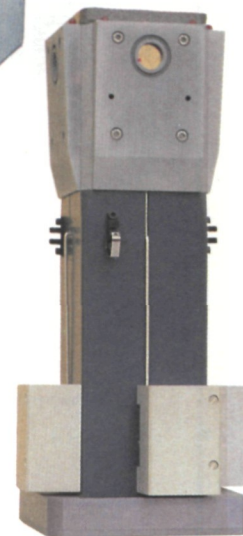
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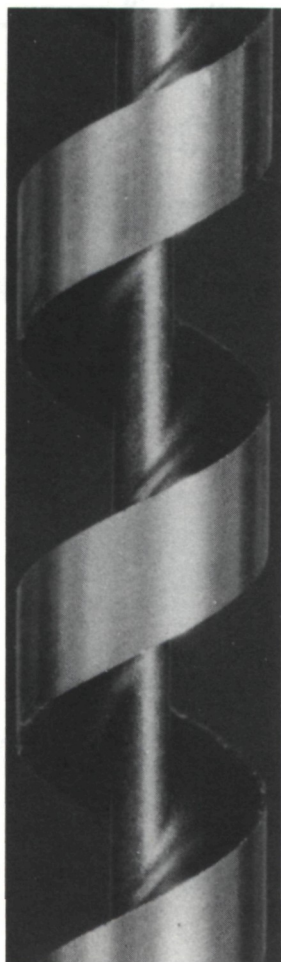
Tube shield

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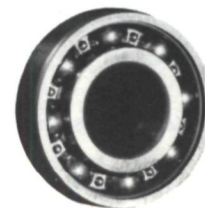
Materials researchers will find this new metallurgical book invaluable in their studies; its organization, selection of materials and use of alphabetical formulae is similar to that of Pearson and Villars and Calvert. The 1990 Metals & Alloys Index Book is designed to be used independently or in conjunction with the Powder Diffraction File (PDF). There are four indexes: the first two provide all materials in the Metals and Alloys PDF and the remaining two contain supporting data.

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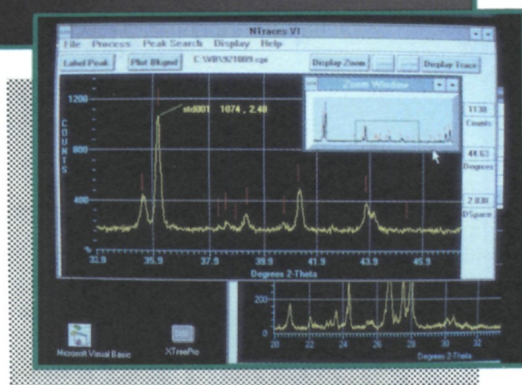
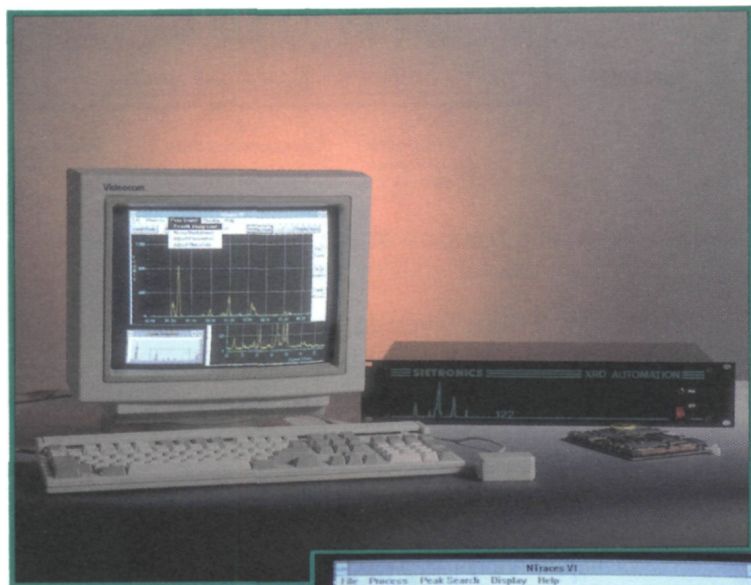
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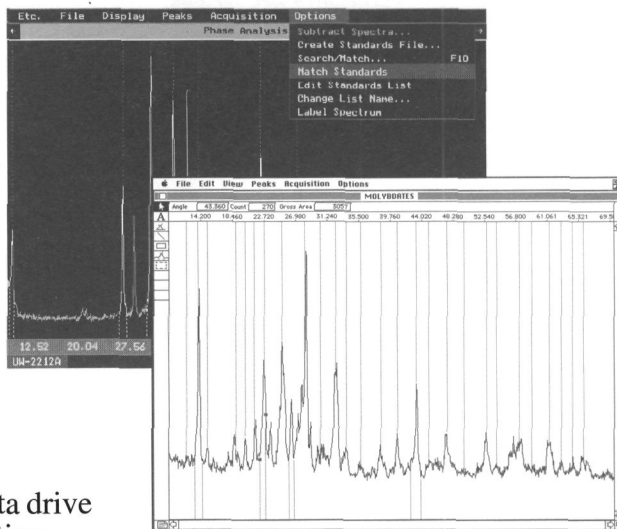
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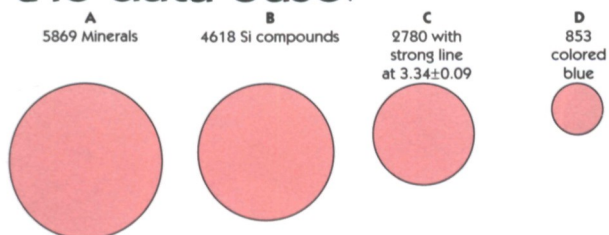
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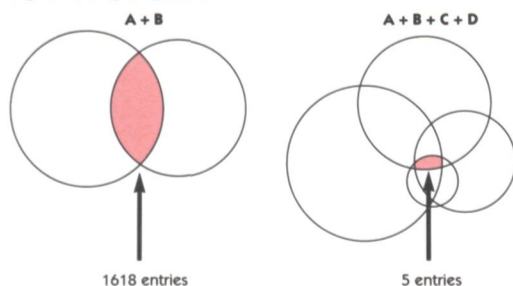
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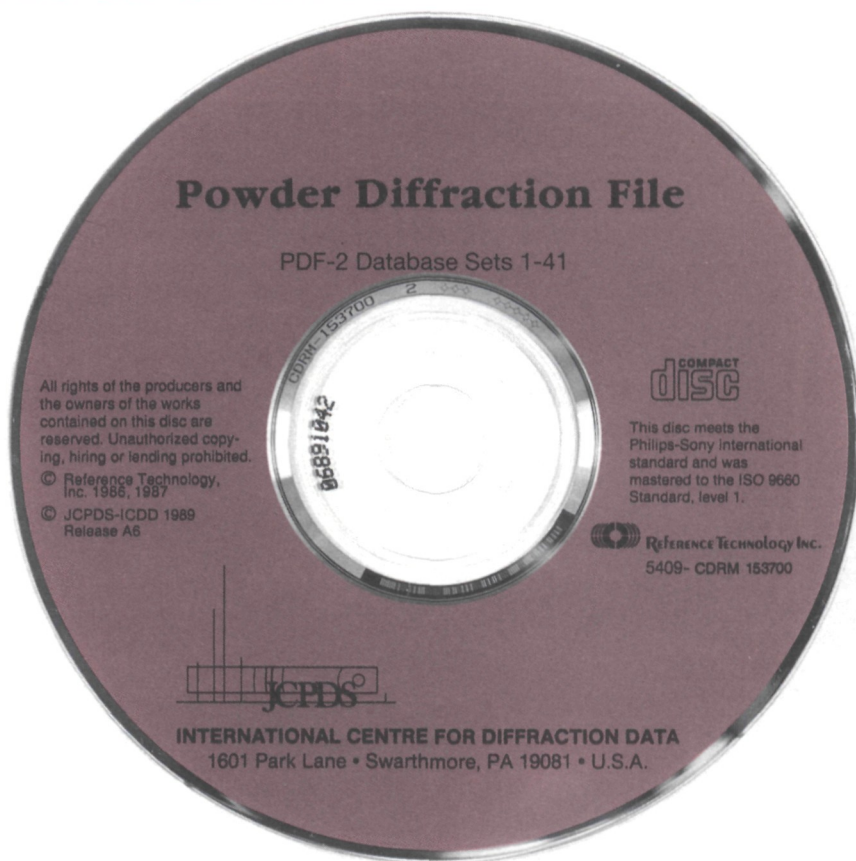
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## Editorial

My last editorial lamented the question of whether editorials are actually read and whether I could get any feedback from readers as to their usefulness. My plea for responses via E-mail did elicit some activity. I received 5 E-mail messages (including Europe and Japan), and also 3 letters with comments and about 10 verbal communications. Actually, this response is encouraging. With around 1300 subscribers to *Powder Diffraction*, this number represents approximately 1% of the distribution. When only 50% of the eligible people vote in public elections and the typical return to a direct-mailed questionnaire is 15 to 25%, 1% response to an editorial should be considered good. Considering that many of the readers do not have ready access to E-mail yet and that not all subscriptions go to individuals, the response is good. I should indicate that my more convenient E-mail address is SMITH@PSUMRL1.PSU.EDU for future correspondence. This address comes directly to the computer on which I do my day-to-day work.

Now that I have initiated a direct line of communication to this editor for readers, I solicit your comments on the articles and other department sections in *Powder Diffraction*. The staff is striving to improve all aspects of the publication, but we do need your input. I did receive some positive comments on the policy of occasionally reprinting one of the classic articles from the past that have influenced powder diffraction research in its early development. I do have some more early papers in mind for future issues, but I would like to receive recommendations from you also. What paper, preferably pre-1960, has significantly influenced your thinking in your own work? Is there some paper in an obscure journal or an

unpublished report that deserves wider circulation and recognition? If so, please relay the suggestion to me. I will always remember a remark made to me by my advisor at the University of Minnesota with respect to the old literature. He claimed to use the older literature, especially the pre-1900 papers, for research ideas. He felt that truly original ideas were very rare and that the older literature had the seeds to nurture but lacked the research facilities to carry out the studies.

*Powder Diffraction* would also like to solicit guest editorials. I usually use this column to announce important meetings, to solicit input to some question such as the use of calculated diffraction patterns and reference intensity ratios, or to disseminate some new ideas on how to improve our field, such as the change in nomenclature for X-ray spectra. Meeting organizers who would like input on planning or educators who arrange workshops involving powder diffraction may find this column appropriate for generating interest. (Actual announcements should be submitted to the Editor for International Reports.) Announcements of round-robin experiments would be very suitable.

I would also encourage those of you who procrastinated about responding to my March request concerning who reads editorials to contact me in some appropriate manner. I would like to prove that editorials do have some usefulness in disseminating information and stimulating thought. If E-mail is not available, then use some other means. I would like to see the response level reach 10%.

Deane K. Smith  
Editor in Chief